## RESPONSE UNDER 37 C.F.R. § 1.116 **EXPEDITED PROCEDURE EXAMINING GROUP 2815**

Attorney Docket No. 5649-1276

PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Young-pil Kim et al.

Examiner: Matthew C. Landau

Serial No.: 10/796,672

Group Art Unit: 2815

Filed: March 9, 2004 For:

Confirmation No.: 3015 SEMICONDUCTOR DEVICE TEST PATTERNS AND RELATED METHODS

FOR PRECISELY MEASURING LEAKAGE CURRENTS IN SEMICONDUCTOR

**CELL TRANSISTORS** 

Date: April 20, 2007

Mail Stop AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## **AMENDMENT**

Sir:

Applicants provide the present Amendment in response to the Office Action mailed January 23, 2007. It is not believed that an extension of time and/or additional fee(s), including fees for net addition of claims-are required, beyond those that may otherwise be provided for in documents accompanying this paper. In the event, however, that an extension of time is necessary to allow consideration of this paper, such an extension is hereby petitioned under 37 C.F.R. §1.136(a). Any additional fees believed to be due in connection with this paper may be charged to our Deposit Account No. 50-0220.

OK. CO Enter